

EV372466807



Inventor: **Fernando Gonzalez et al.**  
Title: **Methods of Forming Semiconductor Circuitry**  
Assignee: **Micron Technology, Inc.**  
Serial No.: **09/989,931**  
Filed: **November 21, 2001 [RCE Filed Herewith]**

**INFORMATION DISCLOSURE STATEMENT**

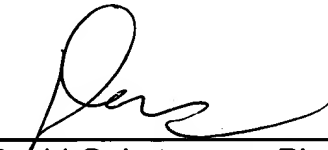
**PURSUANT TO 37 C.F.R. §§ 1.56, 1.97 AND 1.98**

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, the Examiner's attention is directed to the references listed on the attached Form PTO-1449 and copies of which are attached. No admission is made regarding whether all the submitted references are prior art.

Citation of these references is respectfully requested.

Respectfully submitted,

Date: 9/7/04

Attorney:   
David G. Latwesen, Ph.D.  
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Wells St. John P.S.

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Form PT 449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1801		SERIAL NO. 09/989,931			
<div style="position: relative; height: 100px;"> <div style="position: absolute; top: 0; left: 0; width: 100%; height: 100%; border: 1px solid black; border-radius: 50%; text-align: center; line-height: 100px; font-size: 24px; font-weight: bold;">           OFFICE SEP 07 2001 PATENT &amp; TRADEMARK OFFICE         </div> </div>					LIST OF ART CITED BY APPLICANT <small>(Use several sheets if necessary)</small>				APPLICANT: Fernando Gonzalez et al.	
					FILING DATE Nov. 21, 2001 [RCE filed herewith]		GROUP 2815			
<b>U.S. PATENT DOCUMENTS</b>										
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate			
	AA	2001/0045604 A1	11/29/01	Oda et al.						
	AB	2001/0008292 A1	07/19/01	Leobandung et al.						
	AC	2002/ 0019105 A1	02/14/02	Hattori et al.						
	AD									
	AE									
	AF									
	AG									
	AH									
	AI									
<b>FOREIGN PATENT DOCUMENTS</b>										
		Document Number	Date	Country	Class	Subclass	Translation			
							Yes	No		
	AJ									
	AK									
	AL									
<b>OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)</b>										
	AM									
	AN									
	AO									
EXAMINER		DATE CONSIDERED								
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>										